



JAPAN RADIO TEST REPORT

Applicant : Micro-Star Int'l Co.,Ltd.

Address : No.69, Lide St., Zhonghe Dist. New Taipei City 235
Taiwan

Equipment : Wireless Headset

Model No. : MS-8ZC9

Trade Name : msi

GFSK: 0.0295 mW/ MHz
 $\pi/4$ -DQPSK: 0.0217 mW/ MHz
8DPSK: 0.0219 mW/ MHz

Output Power : For AFH Function:
GFSK: 0.1204 mW/ MHz
 $\pi/4$ -DQPSK: 0.0880 mW/ MHz
8DPSK: 0.0890 mW/ MHz

Carrier Sense : ☐Yes ☒No

I HEREBY CERTIFY THAT :

The sample was received on Nov. 14, 2025 and the testing was completed on Nov. 24, 2025 at CerpPASS Technology Corp. The test result refers exclusively to the test presented test model / sample. Without written approval of CerpPASS Technology Corp., the test report shall not be reproduced except in full.

Approval by:


Mark Liao / Supervisor

Laboratory Accreditation:

CerpPASS Technology Corporation Test Laboratory





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History of this test report

Report No.	Issued Date	Description
25110274-TRMIC04	Dec. 23, 2025	Original



1. Summary of Test Procedure and Test Results

1.1 Applicable Standards

“MIC Notification No. 88, Appendix No. 43”

TELEC-T401 (2023-11):

- Item 19 of Article 2

Description	Result
Frequency Error	Pass
Occupied Bandwidth	Pass
RF Output Power Tolerance	Pass
Spurious Emissions(TX)	Pass
Spurious Emissions(RX)	Pass
Interference Prevention Function	Pass
Dwell Time on each channel	Pass
Angular Width of Principal Radiation	Pass
Construction Protection Confirmation	Pass

*The lab has reduced the uncertainty risk factor from test equipment, environment and staff technicians which according to the standard on contract. Therefore, the test result will only be determined by standard requirement, measurement uncertainty evaluation is not considered.

* The following reference test guidance is not within the scope of accreditation of TAF.

–“MIC Notification No. 88, Appendix No. 43”

- Item 19 of Article 2



2. Test Configuration of Equipment under Test

2.1 Feature of Equipment under Test

Operation Frequency Range	BT/SRD: 2400-2483.5MHz
Center Frequency Range	BT/SRD: 2402-2480MHz
Modulation Type	BT: GFSK, $\pi/4$ -DQPSK, 8DPSK SRD: GFSK
Modulation Technology	BT: FHSS SRD: DTS
Data Rate	BT: GFSK: 1Mbps, $\pi/4$ -DQPSK: 2Mbps, 8DPSK: 3Mbps SRD: GFSK: 1Mbps
Antenna Type	PCB Antenna
Antenna Gain	1.9 dBi

Note: For more details, please refer to the User's manual of the EUT.

2.2 Carrier Frequency of Channels

Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)
*00	2402	20	2422	40	2442	60	2462
01	2403	21	2423	41	2443	61	2463
02	2404	22	2424	42	2444	62	2464
03	2405	23	2425	43	2445	63	2465
04	2406	24	2426	44	2446	64	2466
05	2407	25	2427	45	2447	65	2467
06	2408	26	2428	46	2448	66	2468
07	2409	27	2429	47	2449	67	2469
08	2410	28	2430	48	2450	68	2470
09	2411	29	2431	49	2451	69	2471
10	2412	30	2432	50	2452	70	2472
11	2413	31	2433	51	2453	71	2473
12	2414	32	2434	52	2454	72	2474
13	2415	33	2435	53	2455	73	2475
14	2416	34	2436	54	2456	74	2476
15	2417	35	2437	55	2457	75	2477
16	2418	36	2438	56	2458	76	2478
17	2419	37	2439	57	2459	77	2479
18	2420	38	2440	58	2460	*78	2480
19	2421	*39	2441	59	2461	---	---

Note: Channels remarked * are selected to perform test.



2.3 Test Mode and Test Software

a. An executive program, " FCC Assist ver.1.0.2.2" under Windows OS system was executed to transmit and receive data via Bluetooth.

b. The following test modes were performed for the test:

Test Mode	Operating Description
1	GFSK (1Mbps)
2	$\pi/4$ -DQPSK (2Mbps)
3	8DPSK (3Mbps)

Modulation Type	TX CONFIGURATION
GFSK	1TX
$\pi/4$ -DQPSK	1TX
8DPSK	1TX

2.4 Description of Test System

RF Conducted				
Equipment	Brand	Model	Length/Type	Power cord/Length/Type
Notebook	lenovo	S1GL2W	N/A	N/A
testfixture	YD-TECH	MCS-73-LV	N/A	N/A



2.5 General Information of Test

Organization	CerpPASS Technology Corp.		
☒ Test Site	CerpPASS Technology Corporation Test Laboratory Address: No.10, Ln. 2, Lianfu St., Luzhu Dist., Taoyuan City 33848, Taiwan (R.O.C.) Tel: +886-3-3226-888 Fax: +886-3-3226-881		
	FCC	TW1439, TW1079	
	IC	4934E-1, 4934E-2	
	Test Condition	Normal Voltage: 3.7 V Extreme Voltage: 3.33 V and 4.07 V	

Test Item	Test Site	Test Period	Environmental Conditions	Tested By
RF Conducted	RFCON01-NK	2025/11/24	27.3°C / 50%	Leon Huang

2.6 Measurement Uncertainty

ISO/IEC 17025 requires that an estimate of the measurement uncertainties associated with the emissions test results be included in the report. The measurement uncertainties given below are based on a 95% confidence level (based on a coverage factor (k=2))

Measurement Item	Uncertainty
Output power	±1.1dB
Unwanted Emissions Strength	±2.0dB
Bandwidth	±6.5%
Frequency tolerance	±0.31KHz
Dwell Time	±3.5%
Output power	±1.1dB
Unwanted Emissions Strength	±2.0dB



3. Test Equipment and Ancillaries Used for Tests

Test Item	RF Conducted						
Test Site	RFCON01-NK						
Instrument	Manufacturer	Model No	Serial No	Calibration Date	Valid Date	Calibration authority	Calibration method
Spectrum Analyzer	ROHDE & SCHWARZ	FSP 40	100047	2025/03/03	2026/03/02	ETC	C
Attenuator	KEYSIGHT	8491B	MY39250703	2025/02/12	2026/02/11	ETC	C
Cable-0.5m(1G-26.5G)	HUBER SUHNER	SUCOFLEX 102	28422/2	2025/06/06	2026/06/05	ETC	C
Power Meter	Anritsu	ML2495A	1224005	2025/02/12	2026/02/11	ETC	C
Power Sensor	Anritsu	MA2411B	1207295	2025/02/12	2026/02/11	ETC	C
Switch Box	Theda	1-4	TW5451159	NA	NA	N/A	N/A

Note: Calibration Method

- a) : Calibration conducted by the National Institute of Information and Communications Technology(NICT) or a designated calibration agency under Article 102-18 paragraph (1).
- b) : Calibration conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) Japan Calibration Service System.
- c) : Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- d) : Calibration conducted by using other equipment that listed above from a) to c).



4. Transmitter Parameters

4.1 Frequency Error

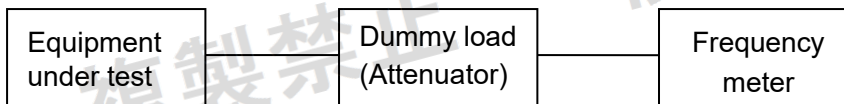
4.1.1 Test Limit

Limits: $\pm 50 \times 10^{-6}$, 50ppm

4.1.2 Test Procedures

According to Notification No. 88 of MIC, 2004, Annex 43, Test item frequency error measuring procedures.

4.1.3 Test Setup



4.1.4 Test Result and Data

GFSK, $\pi/4$ -DQPSK, 8DPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Measured Frequency	MHz	2401.9990	2440.9977	2479.9963
Vnom	Frequency Error	ppm	-0.42	-0.94	-1.49



4.2 Occupied Bandwidth

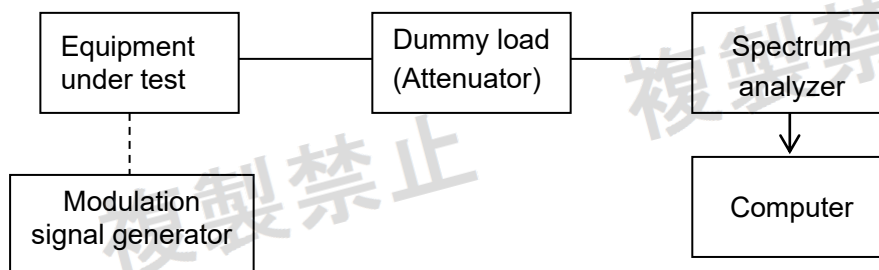
4.2.1 Test Limit

Modulation type	Occupied Band Width
FHSS、FHSS+DSSS、FHSS+OFDM	< 83.5 MHz
DSSS	< 26 MHz
OFDM	< 26 MHz 26 -40MHz
Other	< 26 MHz

4.2.2 Test Procedures

According to Notification No. 88 of MIC, 2004, Annex 43, test item occupied bandwidth and spreading bandwidth, measuring procedures.

4.2.3 Test Setup



4.2.4 Test Result and Data

GFSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Occupied Bandwidth	MHz	78.24		

$\pi/4$ -DQPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Occupied Bandwidth	MHz	78.32		

8DPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Occupied Bandwidth	MHz	78.41		



For AFH Function

GFSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Occupied Bandwidth	MHz	18.66		

$\pi/4$ -DQPSK

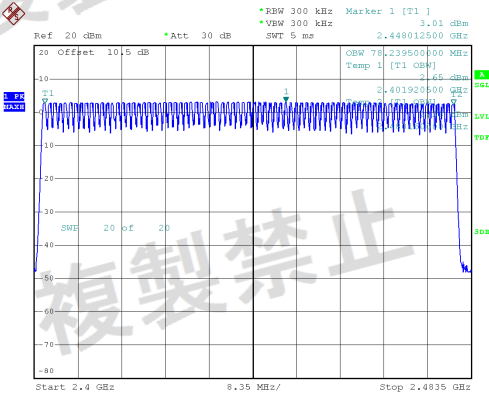
Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Occupied Bandwidth	MHz	19.01		

8DPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Occupied Bandwidth	MHz	18.99		

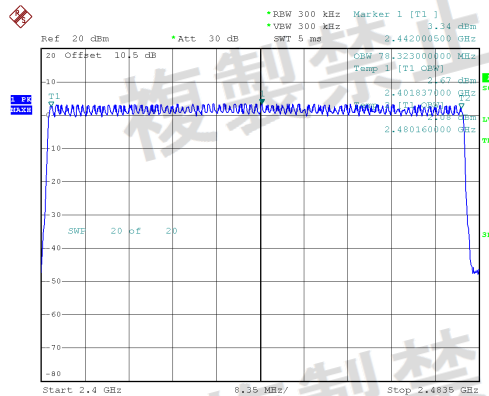


Modulation Standard: GFSK



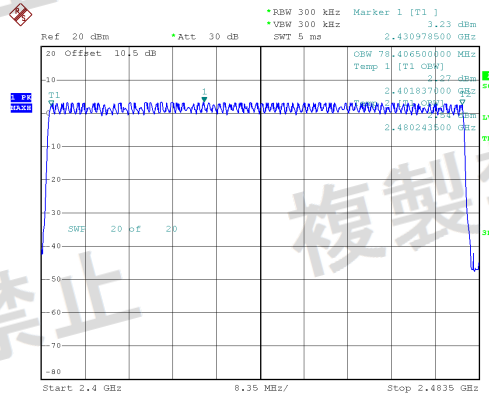
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Modulation Standard: $\pi/4$ -DQPSK



Date: 24.NOV.2025 12:37:34

Modulation Standard: 8DPSK

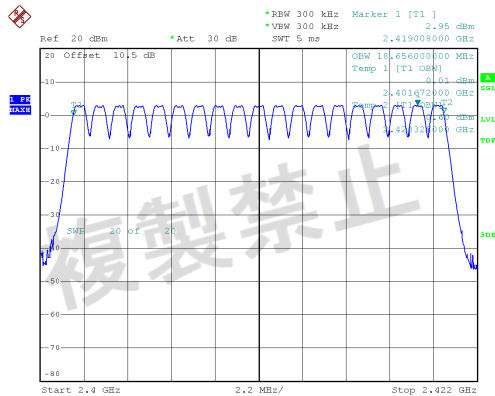


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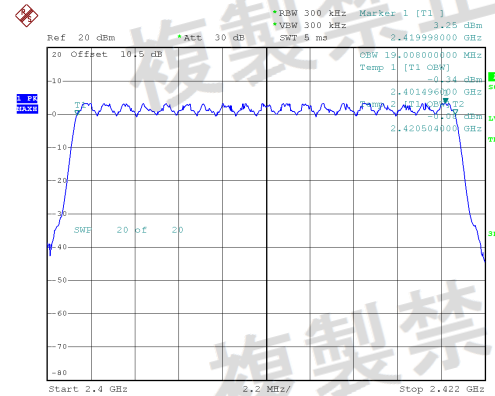
AFH

Modulation Standard: GFSK



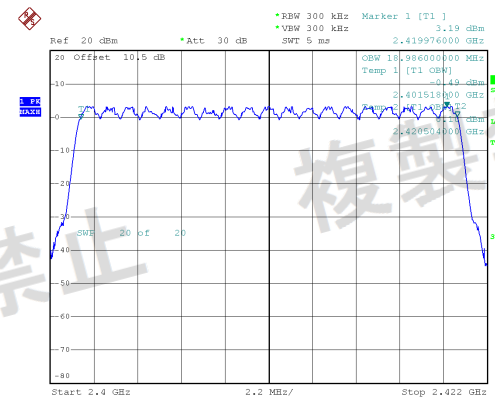
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Modulation Standard: $\pi/4$ -DQPSK



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Modulation Standard: 8DPSK



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4.3 RF Output Power Tolerance

4.3.1 Test Limit

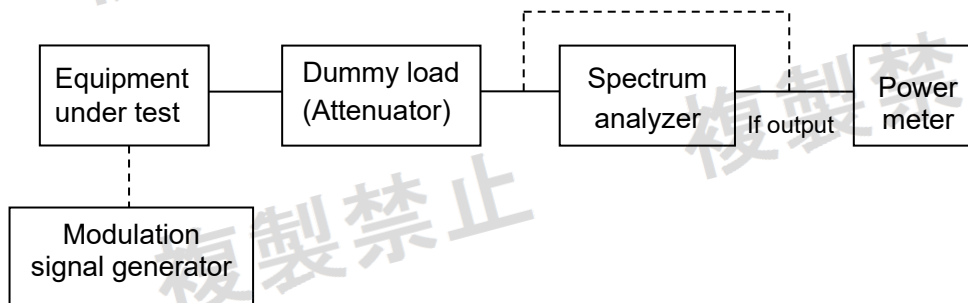
1. tolerance: +20 %
2. output power:

Modulation type	Occupied Band Width	output power
FHSS、FHSS+DSSS、FHSS+OFDM	< 83.5 MHz	< 10mW/MHz
DSSS	< 26 MHz	< 10mW/MHz
OFDM	< 26 MHz	< 10mW/MHz
	26 -40MHz	< 5mW/MHz
Other	< 26 MHz	< 10mW

4.3.2 Test Procedure

According to Notification No. 88 of MIC, 2004, Annex 43, test item antenna power error measuring procedure.

4.3.3 Test Setup



4.3.4 Declared Rated Power

GFSK: 0.0295 mW/ MHz

$\pi/4$ -DQPSK: 0.0217 mW/ MHz

8DPSK: 0.0219 mW/ MHz

For AFH Function:

GFSK: 0.1204 mW/ MHz

$\pi/4$ -DQPSK: 0.0880 mW/ MHz

8DPSK: 0.0890 mW/ MHz



4.3.5 Test Result and Data

GFSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Antenna Power	mW/MHz	0.0283	0.0295	0.0271
Vnom	Antenna Power Error	%	-4.28	0.00	-8.38

$\pi/4$ -DQPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Antenna Power	mW/MHz	0.0207	0.0217	0.0199
Vnom	Antenna Power Error	%	-4.50	0.00	-8.17

8DPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Antenna Power	mW/MHz	0.0208	0.0219	0.0200
Vnom	Antenna Power Error	%	-4.72	0.00	-8.38

For AFH Function

GFSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Antenna Power	mW/MHz	0.1152	0.1204	0.1103
Vnom	Antenna Power Error	%	-4.28	0.00	-8.38

$\pi/4$ -DQPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Antenna Power	mW/MHz	0.0841	0.0880	0.0808
Vnom	Antenna Power Error	%	-4.50	0.00	-8.17

8DPSK

Test Conditions					
Voltage	Test Frequency	MHz	2402	2441	2480
Vnom	Antenna Power	mW/MHz	0.0848	0.0890	0.0815
Vnom	Antenna Power Error	%	-4.72	0.00	-8.38



4.4 Spurious Emissions

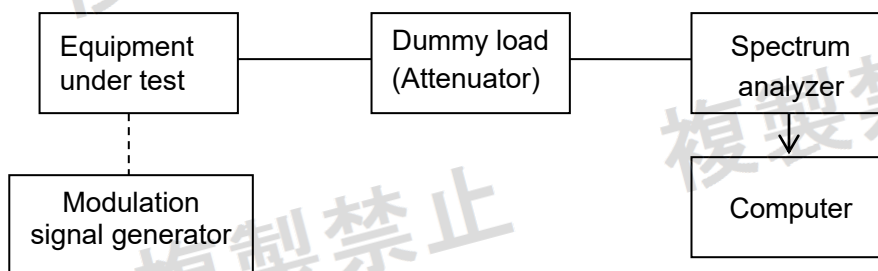
4.4.1 Test Limit

	Frequency Band (For 2400 ~ 2483.5 MHz)	Limit
*1	<2387MHz	2.5 μ W/MHz
*2	2387MHz ~ 2400MHz	25 μ W/MHz
*3	2483.5MHz ~ 2496.5MHz	25 μ W/MHz
*4	>2496.5MHz	2.5 μ W/MHz

4.4.2 Test Procedure

According to Notification No. 88 of MIC, 2004, Annex 43 Spurious and unwanted emission intensity measuring procedure.

4.4.3 Test Setup





4.4.4 Test Result and Data

GFSK

Test Conditions						
Voltage	Frequency Band	Test Frequency	MHz	2402	2441	2480
Vnom	30 MHz~ 2387 MHz	Unwanted Emission Frequency	MHz	2209.93	2249.41	2288.60
Vnom	2387 MHz~ 2400 MHz		MHz	2400.00	2392.05	2394.10
Vnom	2483.5 MHz~ 2496.5 MHz		MHz	2494.88	2488.98	2483.50
Vnom	2496.5 MHz~ 12500 MHz		MHz	4803.56	4882.33	4959.86
Vnom	30 MHz~ 2387 MHz	Unwanted Emission Intensity	μW	0.0294	0.0387	0.0506
Vnom	2387 MHz~ 2400 MHz		μW	9.1201	0.0229	0.0096
Vnom	2483.5 MHz~ 2496.5 MHz		μW	0.0089	0.0233	0.3090
Vnom	2496.5 MHz~ 12500 MHz		μW	0.0684	0.0855	0.1330

*The test result calculated as follows: $\mu W = 10^{(\text{Measurement Value(dBm)}/10)} * 1000$

π/4-DQPSK

Test Conditions						
Voltage	Frequency Band	Test Frequency	MHz	2402	2441	2480
Vnom	30 MHz~ 2387 MHz	Unwanted Emission Frequency	MHz	2209.93	2249.41	2288.60
Vnom	2387 MHz~ 2400 MHz		MHz	2399.99	2397.70	2395.60
Vnom	2483.5 MHz~ 2496.5 MHz		MHz	2485.74	2488.63	2483.50
Vnom	2496.5 MHz~ 12500 MHz		MHz	4803.56	4881.08	4959.86
Vnom	30 MHz~ 2387 MHz	Unwanted Emission Intensity	μW	0.0292	0.0376	0.0468
Vnom	2387 MHz~ 2400 MHz		μW	17.7828	0.0256	0.0096
Vnom	2483.5 MHz~ 2496.5 MHz		μW	0.0090	0.0248	0.4188
Vnom	2496.5 MHz~ 12500 MHz		μW	0.1432	0.1648	0.1496

*The test result calculated as follows: $\mu W = 10^{(\text{Measurement Value(dBm)}/10)} * 1000$

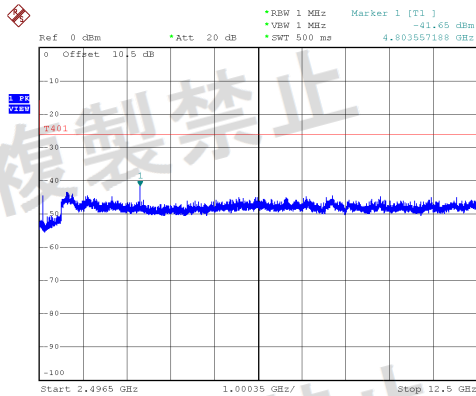
8DPSK

Test Conditions						
Voltage	Frequency Band	Test Frequency	MHz	2402	2441	2480
Vnom	30 MHz~ 2387 MHz	Unwanted Emission Frequency	MHz	2209.93	2249.12	2288.30
Vnom	2387 MHz~ 2400 MHz		MHz	2400.00	2392.73	2396.82
Vnom	2483.5 MHz~ 2496.5 MHz		MHz	2496.12	2483.77	2483.51
Vnom	2496.5 MHz~ 12500 MHz		MHz	4803.56	4882.33	4959.86
Vnom	30 MHz~ 2387 MHz	Unwanted Emission Intensity	μW	0.0292	0.0383	0.0480
Vnom	2387 MHz~ 2400 MHz		μW	16.3682	0.0244	0.0096
Vnom	2483.5 MHz~ 2496.5 MHz		μW	0.0096	0.0256	0.4018
Vnom	2496.5 MHz~ 12500 MHz		μW	0.1535	0.1738	0.1936

*The test result calculated as follows: $\mu W = 10^{(\text{Measurement Value(dBm)}/10)} * 1000$



Modulation Standard: GFSK, CH00

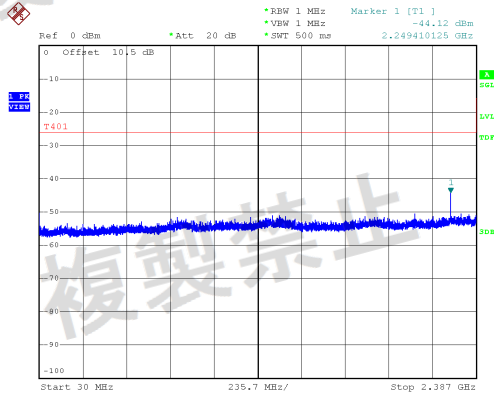


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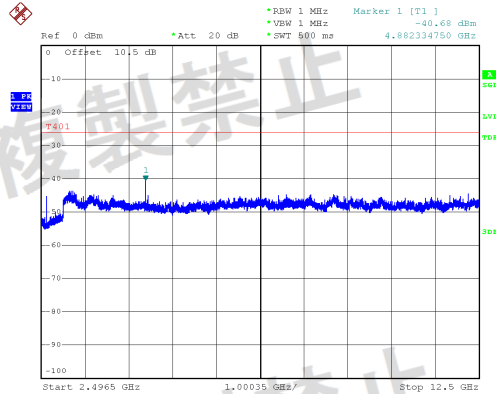
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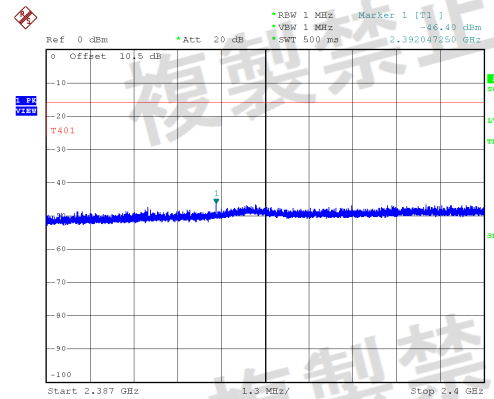
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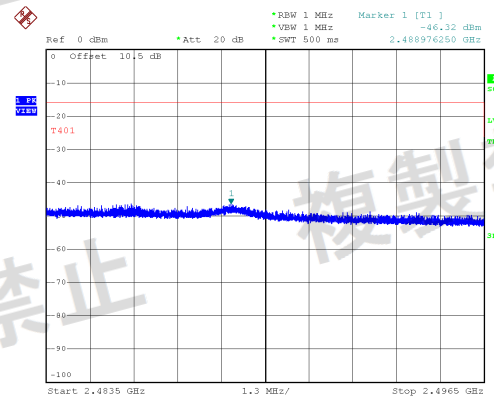
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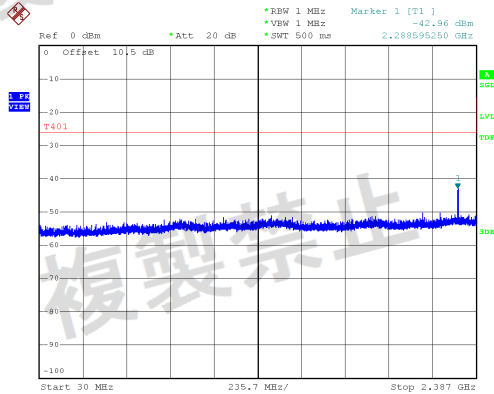
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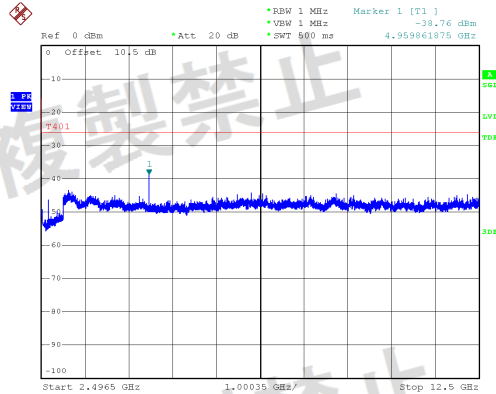
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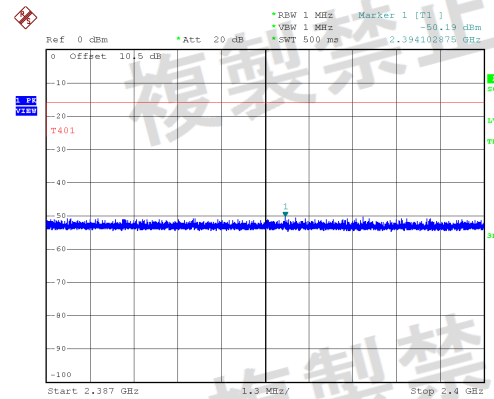
Modulation Standard: GFSK, CH78



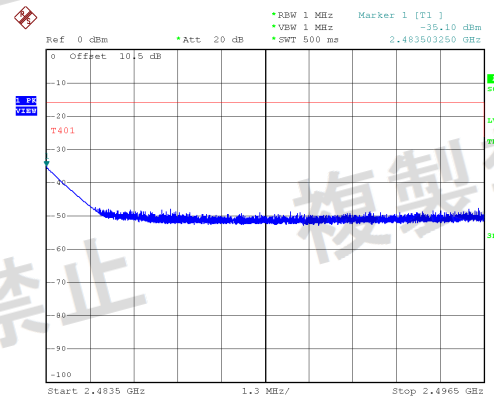
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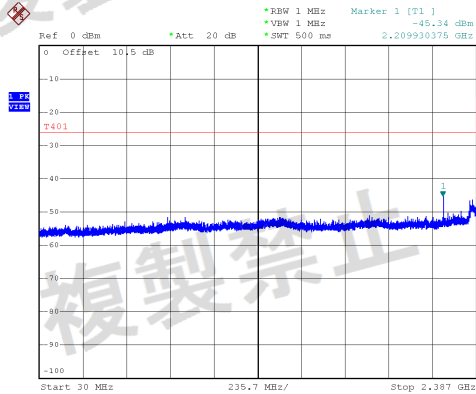
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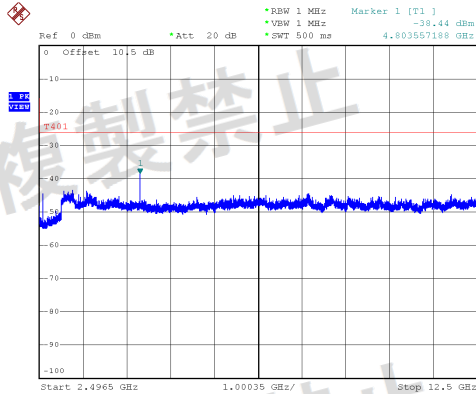
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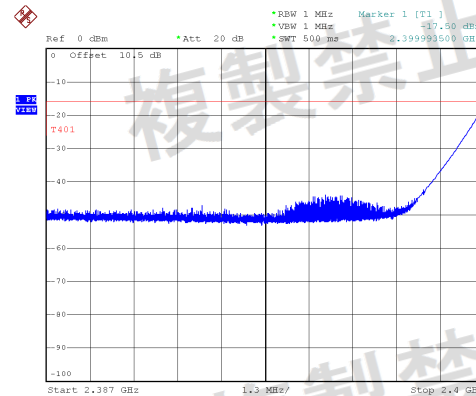
Modulation Standard: $\pi/4$ -DQPSK, CH00



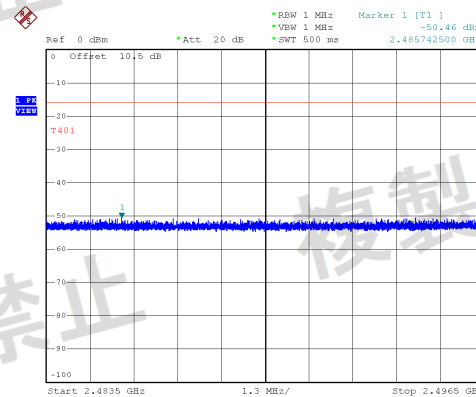
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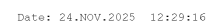
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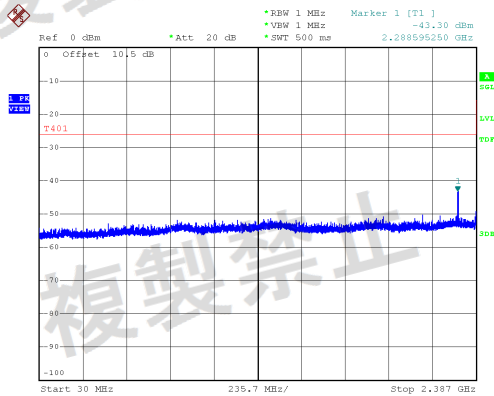


Modulation Standard: $\pi/4$ -DQPSK, CH39

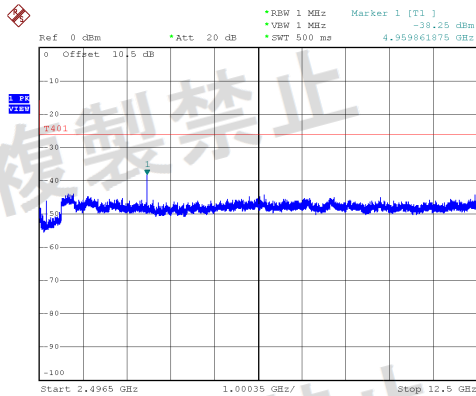




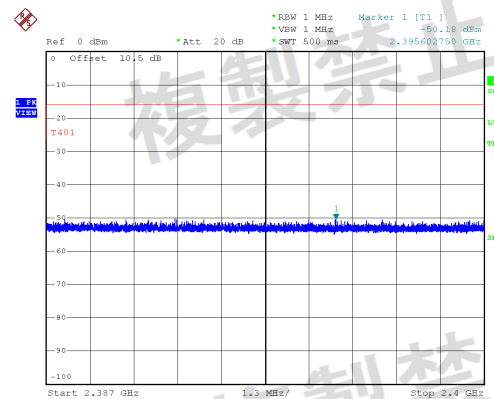
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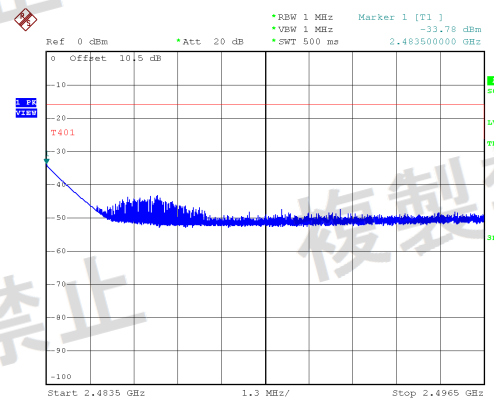
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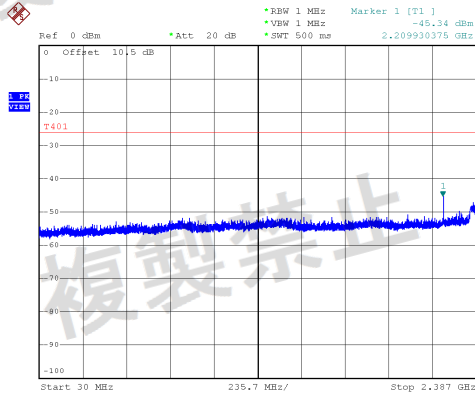
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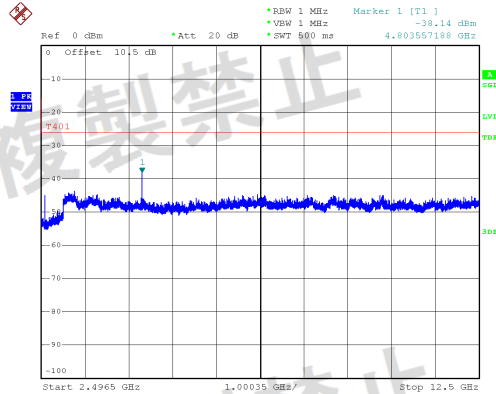
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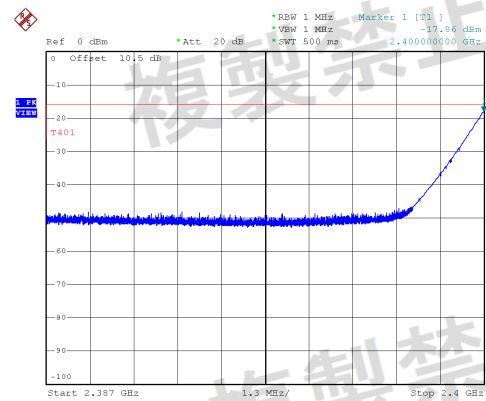
Modulation Standard: 8DPSK, CH00



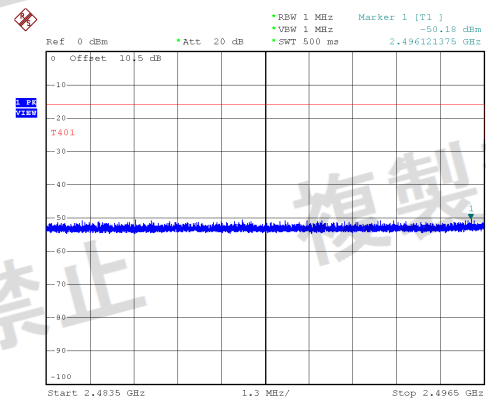
Date: 24.NOV.2025 13:07:04



Date: 24.NOV.2025 13:08:50



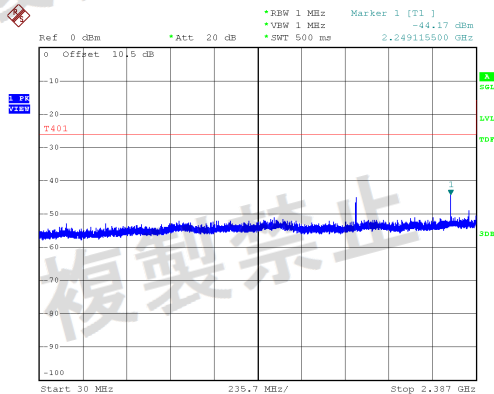
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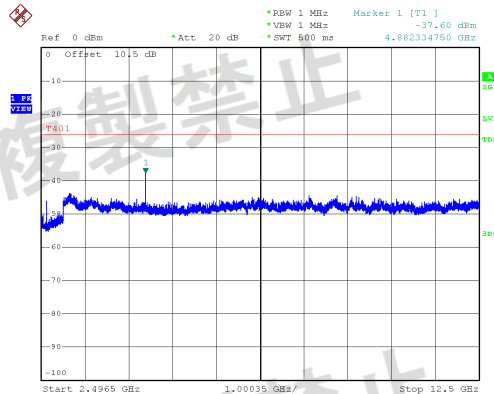
Date: 24.NOV.2025 13:08:17



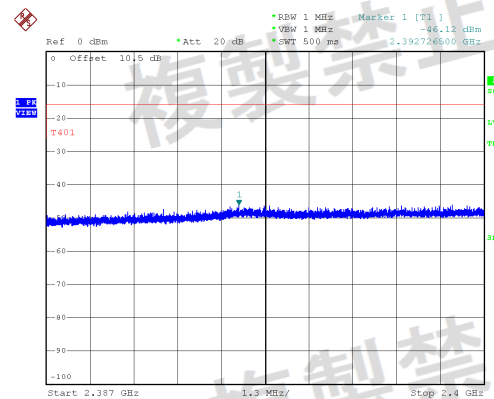
Modulation Standard: 8DPSK, CH39



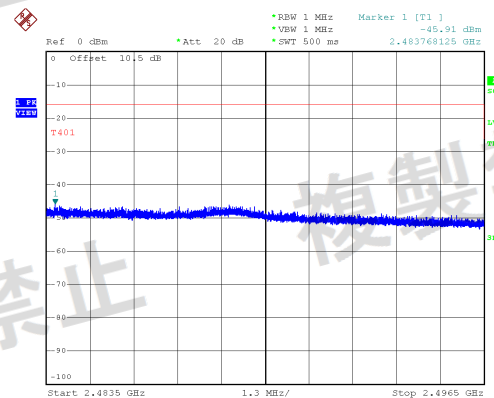
Date: 24.NOV.2025 13:10:31



Date: 24.NOV.2025 13:12:18



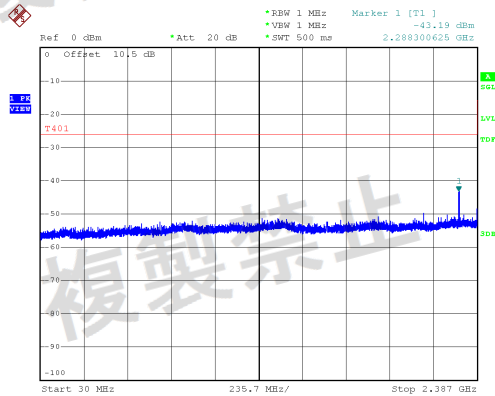
Date: 24.NOV.2025 13:11:07



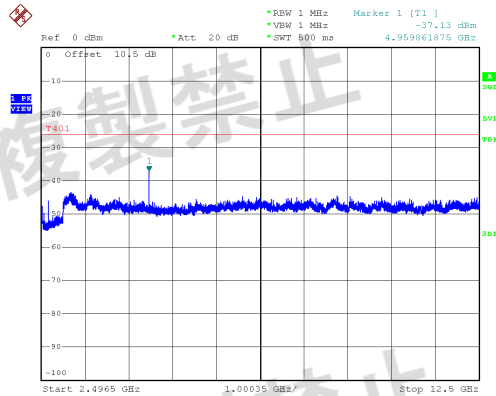
Date: 24.NOV.2025 13:11:43



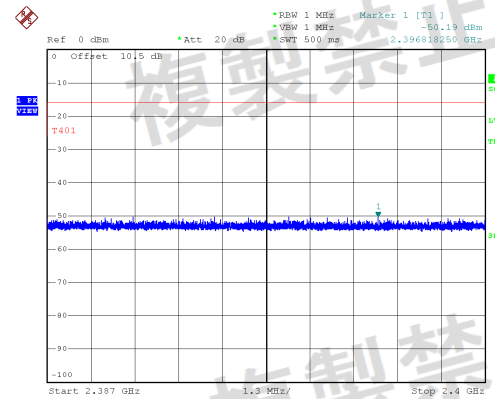
Modulation Standard: 8DPSK, CH78



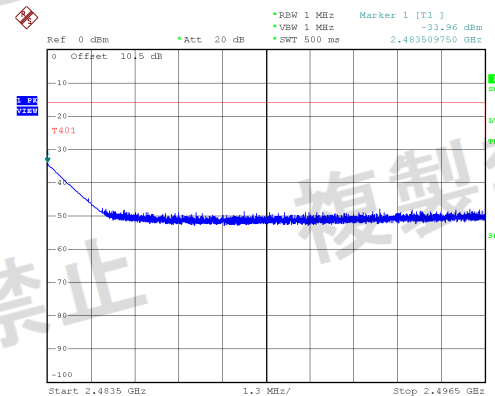
Date: 24.NOV.2025 13:14:08



Date: 24.NOV.2025 13:15:54



Date: 24.NOV.2025 13:14:43



Date: 24.NOV.2025 13:15:19



4.5 Dwell Time on each channel

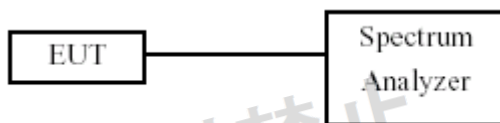
4.5.1 Test Limit

The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed.

4.5.2 Test Procedure

According to Notification No. 88 of MIC, 2004, Annex 43, test item" Holding time of hopping frequency", measuring procedures.

4.5.3 Test Setup



4.5.4 Test Result and Data

GFSK

Frequency	MHz	2402	2441	2480
Dwell Time	ms	275.02	275.02	275.02

Result: Pass

$\pi/4$ -DQPSK

Frequency	MHz	2402	2441	2480
Dwell Time	ms	277.53	277.53	277.53

Result: Pass

8DPSK

Frequency	MHz	2402	2441	2480
Dwell Time	ms	276.87	276.87	276.87

Result: Pass

For AFH Function

GFSK

Frequency	MHz	2402	2441	2480
Dwell Time	ms	266.62	266.62	266.62

Result: Pass

$\pi/4$ -DQPSK

Frequency	MHz	2402	2441	2480
Dwell Time	ms	270.48	270.48	270.48

Result: Pass

8DPSK

Frequency	MHz	2402	2441	2480
Dwell Time	ms	268.78	268.78	268.78

Result: Pass



4.6 Interference Prevention Function

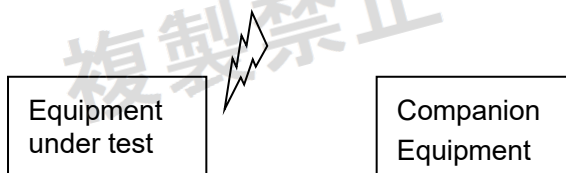
4.6.1 Test Limit

Identification code ≥ 48 bits

4.6.2 Test Procedures

1. Set EUT under operation mode and link up with companion equipment
2. Check communication status between EUT and companion equipment is normal
3. Confirm the MAC address of EUT

4.6.3 Test Setup



4.6.4 Test Result

ID Code	MAC Address : 2C : F0 : 5D : 10 : 00 : B5
Result : PASS	



4.7 Carrier Sensing Function

4.7.1 Test Result

Not applicable



5. Receiver Parameters

5.1 Spurious Emissions

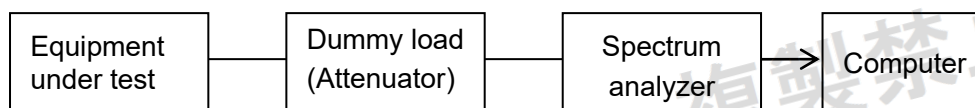
5.1.1 Test Limit

Frequency Band	Limit
<1GHz	4nW
1GHz ~ 12.5GHz	20nW

5.1.2 Test Procedures

According to Notification No. 88 of MIC, 2004, Annex 43 Limit of secondary radiated emissions measuring procedure.

5.1.3 Test Setup





5.1.4 Test Result and Data

GFSK

Test Conditions						
Voltage	Frequency Band	Test Frequency	MHz	2402	2441	2480
Vnom	30 MHz~ 1000 MHz	Spurious Emission Frequency	MHz	848.07	338.46	517.06
Vnom	1000 MHz~ 12500 MHz		MHz	8561.25	3609.06	3127.50
Vnom	30 MHz~ 1000 MHz	Spurious Emission Intensity	nW	0.0237	0.0243	0.0242
Vnom	1000 MHz~ 12500 MHz		nW	0.4345	0.3945	0.4315

*The test result calculated as follows: $nW = 10^{(\text{Measurement Value(dBm)}/10)} * 1000000$

$\pi/4$ -DQPSK

Test Conditions						
Voltage	Frequency Band	Test Frequency	MHz	2402	2441	2480
Vnom	30 MHz~ 1000 MHz	Spurious Emission Frequency	MHz	862.62	590.30	995.39
Vnom	1000 MHz~ 12500 MHz		MHz	3070.00	3124.63	3134.69
Vnom	30 MHz~ 1000 MHz	Spurious Emission Intensity	nW	0.0246	0.0261	0.0252
Vnom	1000 MHz~ 12500 MHz		nW	0.3855	0.4217	0.3981

*The test result calculated as follows: $nW = 10^{(\text{Measurement Value(dBm)}/10)} * 1000000$

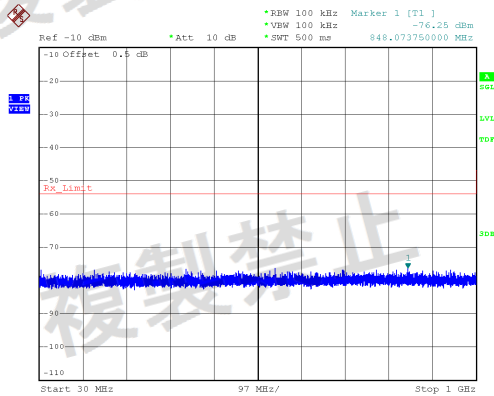
8DPSK

Test Conditions						
Voltage	Frequency Band	Test Frequency	MHz	2402	2441	2480
Vnom	30 MHz~ 1000 MHz	Spurious Emission Frequency	MHz	855.11	837.89	840.56
Vnom	1000 MHz~ 12500 MHz		MHz	9156.38	3062.81	3162.00
Vnom	30 MHz~ 1000 MHz	Spurious Emission Intensity	nW	0.0299	0.0275	0.0246
Vnom	1000 MHz~ 12500 MHz		nW	0.3828	0.3681	0.4111

*The test result calculated as follows: $nW = 10^{(\text{Measurement Value(dBm)}/10)} * 1000000$

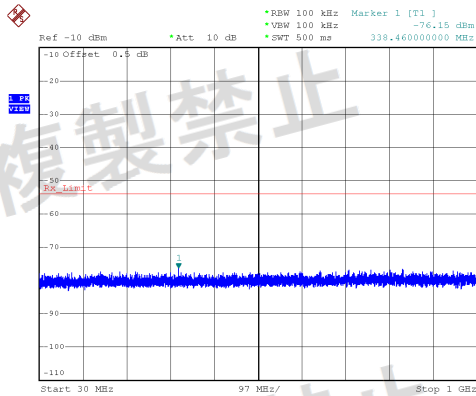


Modulation Standard: GFSK, CH00

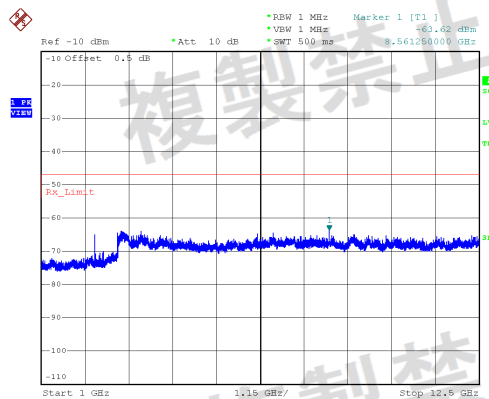


Date: 24.NOV.2025 10:47:12

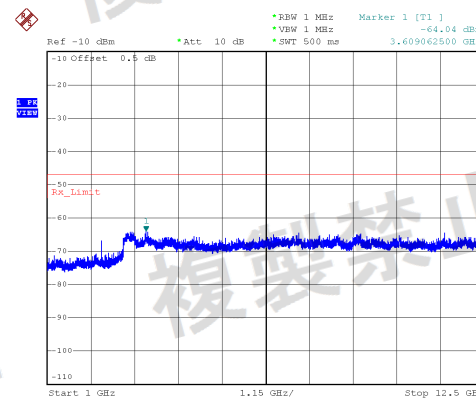
Modulation Standard: GFSK, CH39



Date: 24.NOV.2025 12:09:35



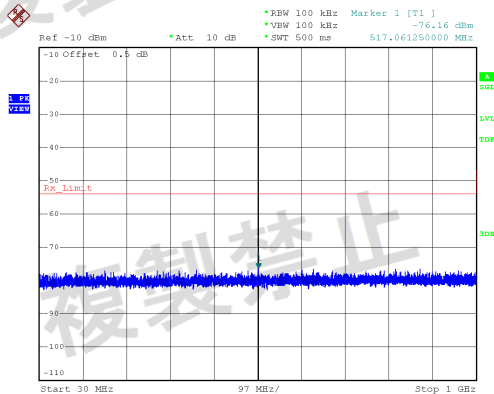
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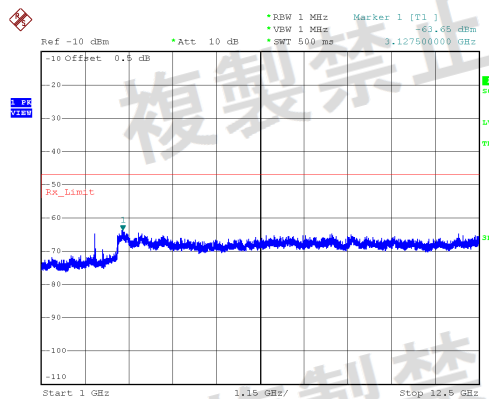
Date: 24.NOV.2025 12:10:10



Modulation Standard: GFSK, CH78



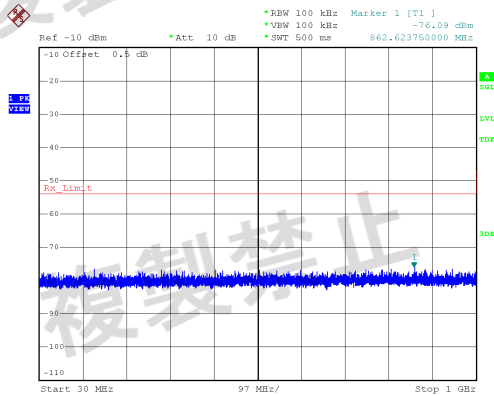
Date: 24.NOV.2025 12:11:28



Date: 24.NOV.2025 12:12:43

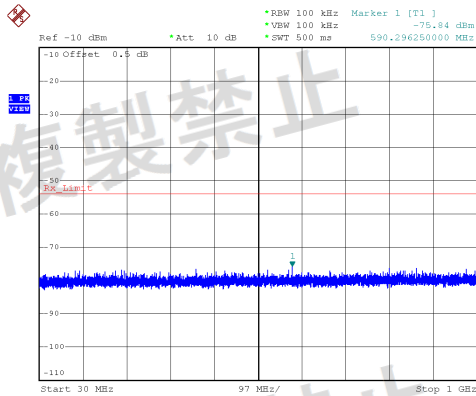


Modulation Standard: $\pi/4$ -DQPSK, CH00

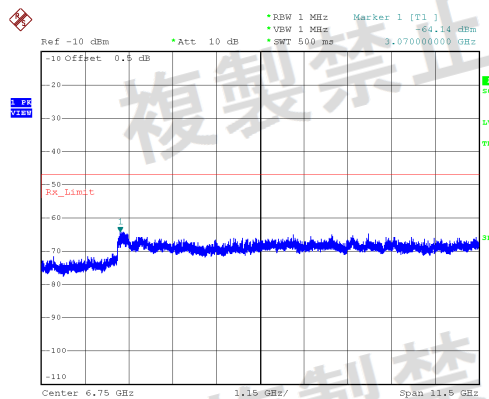


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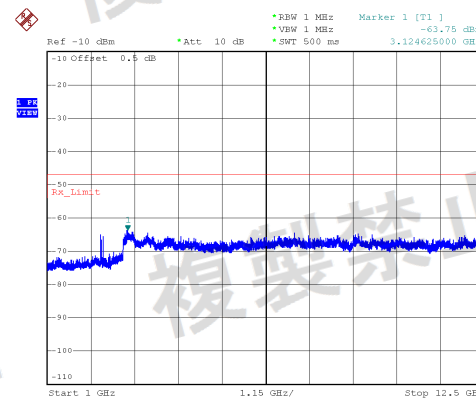
Modulation Standard: $\pi/4$ -DQPSK, CH39



Date: 24.NOV.2025 12:57:45



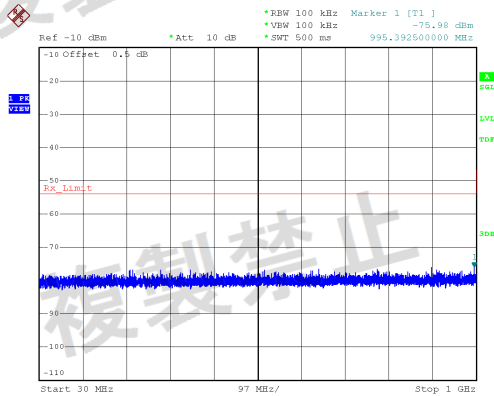
Date: 24.NOV.2025 12:56:35



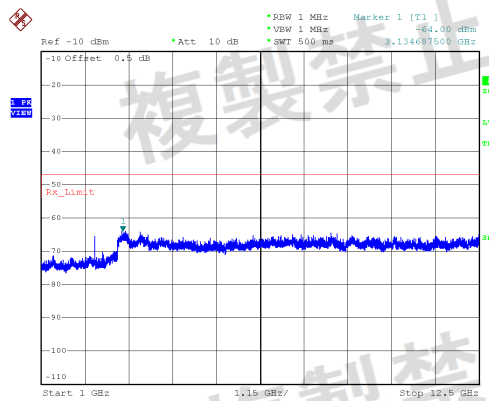
Date: 24.NOV.2025 12:58:20



Modulation Standard: $\pi/4$ -DQPSK, CH78



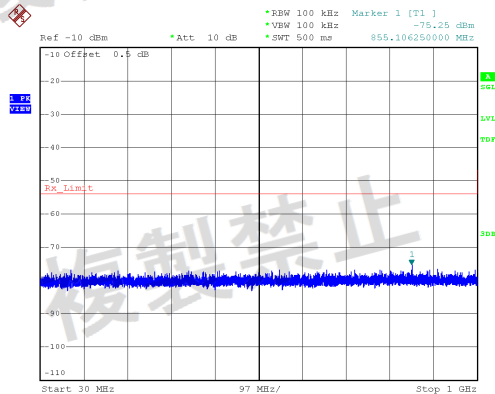
Date: 24.NOV.2025 12:59:08



Date: 24.NOV.2025 12:59:43

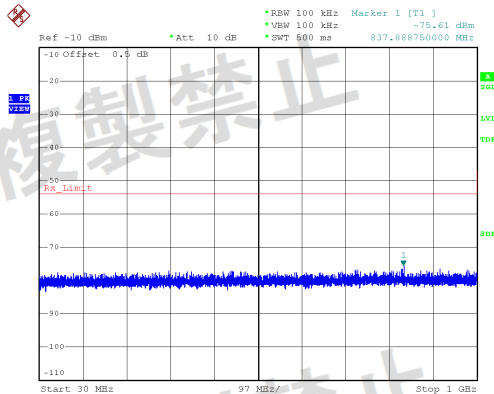


Modulation Standard: 8DPSK, CH00

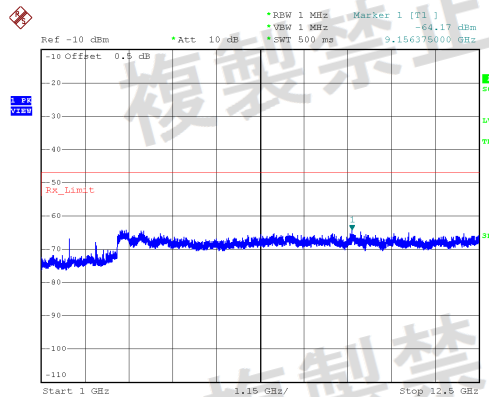


Date: 24.NOV.2025 13:31:17

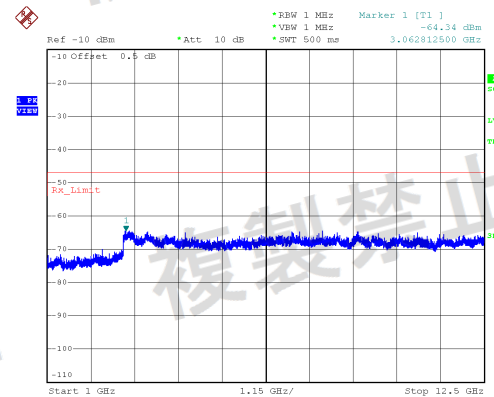
Modulation Standard: 8DPSK, CH39



Date: 24.NOV.2025 13:32:57



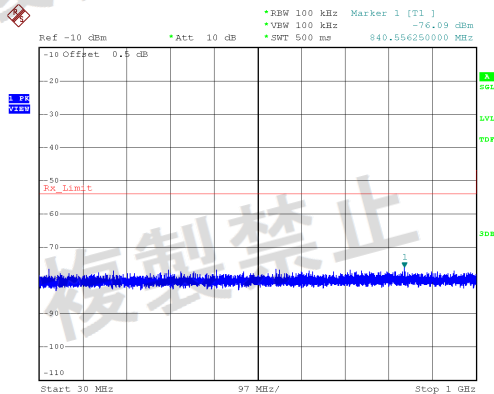
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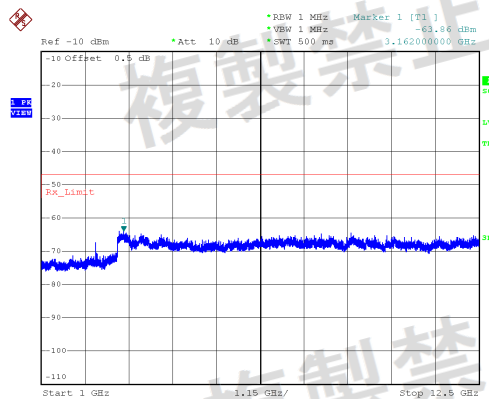
Date: 24.NOV.2025 13:33:33



Modulation Standard: 8DPSK, CH78



Date: 24.NOV.2025 13:34:18



Date: 24.NOV.2025 13:34:53



6. Angular Width of Principal Radiation

6.1 Test Result

Antenna Type	PCB
Antenna Gain	1.90
Cable Loss (dB)	0.50
EIRP (dBm/MHz)	-13.40
Half Power Beam Angles (deg)	360.00
Limit of E.I.R.P (dBm/MHz)	6.91
Result	Pass



7. Power Supply Voltage Fluctuation Test

Voltage Fluctuation Test	Normal Voltage	High Voltage + 10% of Normal Voltage	Low Voltage - 10% of Normal Voltage
Input DC Power	3.7	4.07	3.33
Output DC Power	3.018	3.021	3.015
Voltage Variation (%)	-	0.10%	-0.10%

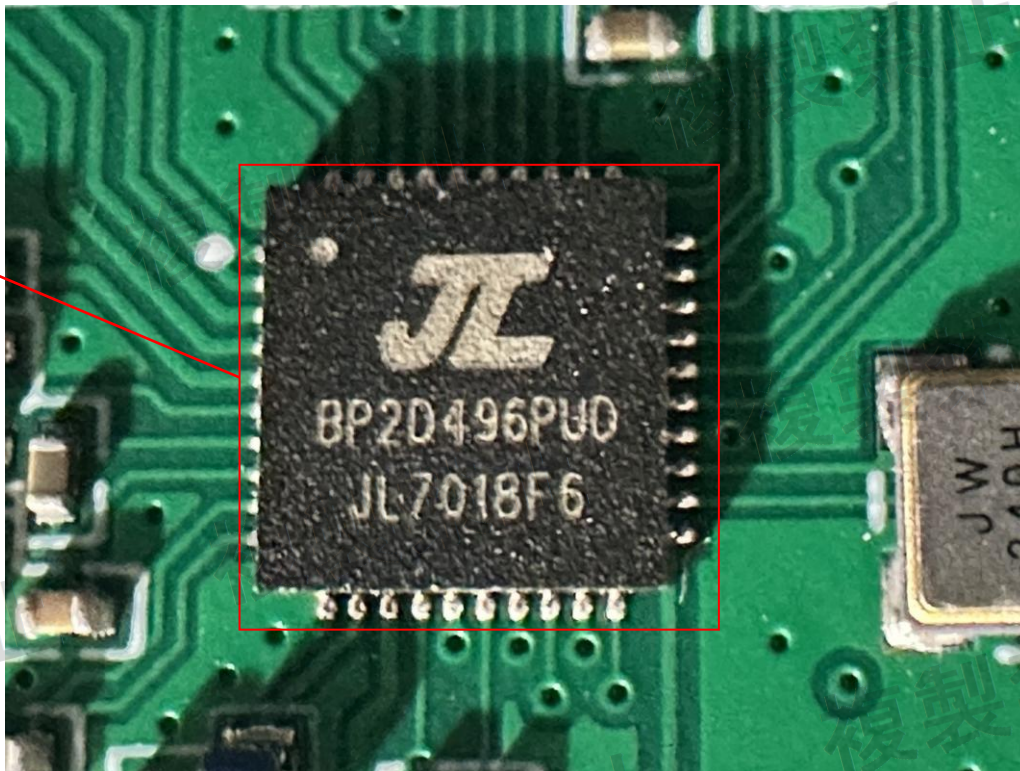
Note: Voltage Variation(%)=(Output High or Low Voltage - Output Normal Voltage)/Output Normal Voltage X 100 During the supply voltage to the EUT from the external power source is varied by +/- 10%,if output voltage had been confirmed that the fluctuation of power supply to the RF circuit of EUT (excluding power source) is equal to or less than +/- 1%, Exempt extremely high and low supply voltage condition tests ,EUT only operated in normal voltage to test all regulations.



8. Construction Protection Confirmation

The Radio Equipment:
☐ Use Special Screw
☐ Metal Shielding is Soldered
☐ Use Ball Grid Array (BGA)
☐ The RF part is covered by glue.
☐ Ultrasonic Welding
Module/Chip:
■ RF module/Chip Pins > 20 and Chip Pins distance < 1.5 mm

RF Chip



-----THE END OF REPORT-----